

Amendments to the Claims:

Claims 1 through 3 have been amended herein. Please note that all claims currently pending and under consideration in the referenced application are shown below. Please enter these claims as amended. This listing of claims will replace all prior versions and listings of claims in the application.

Listing of Claims:

1. (Currently Amended) A testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
establishing an enhanced reliability testing flag for an integrated circuit device resulting from fabrication errors and manufacturing deviations from a manufacturing process for an integrated circuit device of a plurality of integrated circuit devices;
storing an enhanced reliability testing flag in the integrated circuit device associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires enhanced reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices when each integrated circuit device of the plurality of integrated circuit devices forms a portion of a wafer;
accessing the enhanced reliability testing flag stored for the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
sorting the plurality of integrated circuit devices in accordance with whether their enhanced reliability testing flag indicates they are in need of the enhanced reliability testing; and
performing the enhanced reliability testing for each integrated circuit device of the plurality of integrated circuit devices requiring the enhanced reliability testing.

2. (Currently Amended) A reliability testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
establishing an enhanced reliability testing flag for an integrated circuit device resulting from fabrication errors and manufacturing deviations from a manufacturing process for an integrated circuit device of a plurality of integrated circuit devices;
storing a reliability testing flag in the integrated circuit device associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the reliability testing flag stored for each unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and
performing the further reliability testing for each integrated circuit device of the plurality of integrated circuit devices requiring the further reliability testing.

3. (Currently Amended) A manufacturing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
establishing an enhanced reliability testing flag for an integrated circuit device resulting from fabrication errors and manufacturing deviations from a manufacturing process for an integrated circuit device of a plurality of integrated circuit devices;
storing a reliability testing flag in the integrated circuit device associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;

accessing the reliability testing flag stored for each unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and
performing the further reliability testing for each integrated circuit device of the plurality of integrated circuit devices requiring the further reliability testing.